

<b>Notice of References Cited</b>	Application/Control No. 10/756,381		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0018643	02-2002	Okada et al.	386/95
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	K	US-			
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**NON-PATENT DOCUMENTS**

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